

Di-*n*-butylbis(thiophene-2-carboxylato-*O,O'*)tin(IV)

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Key indicators

Single-crystal X-ray study
 $T = 173$ K
 Mean $\sigma(\text{C}-\text{C}) = 0.004$ Å
 Disorder in main residue
 R factor = 0.024
 wR factor = 0.061
 Data-to-parameter ratio = 24.0

For details of how these key indicators were automatically derived from the article, see <http://journals.iucr.org/e>.

The title compound, $[\text{Sn}(\text{C}_4\text{H}_9)_2(\text{C}_5\text{H}_3\text{O}_2\text{S})_2]$, crystallizes with two molecules in the asymmetric unit, differing just in the orientation of one of the *n*-butyl groups. The carboxylate groups asymmetrically chelate the Sn atom.

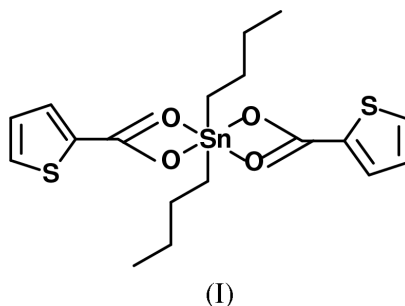
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Comment

Organotin carboxylates have been the subject of several investigations in recent years (Meriem *et al.*, 1990; Meunier-Piret *et al.*, 1993; Gielen *et al.*, 1995). They are of interest because of their potential pharmaceutical applications, especially their significant antitumoral activity (Meriem *et al.*, 1991). We have performed the crystal structure determination of the title compound, (I), in order to determine its conformation. It crystallizes with two molecules in the asymmetric unit, which differ only in the orientation of one *n*-butyl group. The thiophenecarboxylate groups binding the same Sn atom are nearly coplanar and are asymmetrically chelating.



Experimental

The title compound was prepared by refluxing a suspension of 10 mmol dibutyltin oxide in a solution of 20 mmol 2-thiophenic acid in a mixture of 150 ml chloroform and 50 ml ethanol for 5 h. The product was distilled off and evaporated under vacuum. Crystals suitable for structure determination were obtained from an ethanol solution.

Crystal data

$[\text{Sn}(\text{C}_4\text{H}_9)_2(\text{C}_5\text{H}_3\text{O}_2\text{S})_2]$
 $M_r = 487.18$
 Monoclinic, $P2_1/c$
 $a = 18.238$ (2) Å
 $b = 21.984$ (3) Å
 $c = 10.586$ (1) Å
 $\beta = 94.051$ (6)°
 $V = 4233.8$ (8) Å³
 $Z = 8$

$D_x = 1.529$ Mg m⁻³
 Mo $K\alpha$ radiation
 Cell parameters from 507 reflections
 $\theta = 2-25^\circ$
 $\mu = 1.42$ mm⁻¹
 $T = 173$ (2) K
 Plate, colourless
 $0.50 \times 0.40 \times 0.20$ mm

Data collection

Siemens CCD three-circle diffractometer
 ω scans
 Absorption correction: empirical (SADABS; Sheldrick, 1996)
 $T_{\min} = 0.537$, $T_{\max} = 0.764$
 76 863 measured reflections
 10 902 independent reflections
 9631 reflections with $I > 2\sigma(I)$

$R_{\text{int}} = 0.023$
 $\theta_{\text{max}} = 29.7^\circ$
 $h = -24 \rightarrow 22$
 $k = -30 \rightarrow 30$
 $l = -13 \rightarrow 14$
 123 standard reflections
 frequency: 1000 min
 intensity decay: none

Refinement

Refinement on F^2
 $R[F^2 > 2\sigma(F^2)] = 0.024$
 $wR(F^2) = 0.061$
 $S = 1.13$
 10 902 reflections
 455 parameters
 H-atom parameters constrained

$w = 1/[\sigma^2(F_o^2) + (0.0258P)^2 + 2.4763P]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\text{max}} = 0.005$
 $\Delta\rho_{\text{max}} = 0.40 \text{ e } \text{\AA}^{-3}$
 $\Delta\rho_{\text{min}} = -0.78 \text{ e } \text{\AA}^{-3}$

Table 1

Selected geometric parameters (Å).

Sn1—O11	2.1233 (13)	Sn1A—O11A	2.1268 (14)
Sn1—O21	2.1248 (13)	Sn1A—O21A	2.1503 (14)
Sn1—O22	2.5553 (14)	Sn1A—O12A	2.4967 (17)
Sn1—O12	2.5641 (14)	Sn1A—O22A	2.5407 (16)

The two thiophene rings are disordered. The resolution of the data did not allow for distinguishing two distinct positions for the S and C atoms. Only one peak was found for each atom in the difference map. Thus, a C and an S atom were refined sharing the same position and the same displacement parameters, and just refining the site-occupation factor of the respective C and S atoms in order to determine the ratio of the different orientations, which turned out to be 0.644 (3) for S13 and C16, 0.810 (3) for S23 and C26, 0.760 (3) for S13A and C16A, and 0.904 (3) for S23A and C26A. All H atoms were located by difference Fourier synthesis and refined with fixed individual displacement parameters [$U(\text{H}) = 1.2U_{\text{eq}}(\text{C})$ or $U(\text{H}) = 1.5U_{\text{eq}}(\text{C}_{\text{methyl}})$] using a riding model with aromatic C—H = 0.95 Å, methyl C—H = 0.98 Å or methylene C—H = 0.99 Å.

Data collection: SMART (Siemens, 1995); cell refinement: SMART; data reduction: SAINT (Siemens, 1995); program(s) used to solve structure: SHELXS97 (Sheldrick, 1990); program(s) used to refine structure: SHELXL97 (Sheldrick, 1997); molecular graphics: XP in SHELXTL-Plus (Sheldrick, 1991); software used to prepare material for publication: SHELXL97.

References

Gielen, M., Bouhbid, A. & Tiekink, E. R. T. (1995). *Main Group Met. Chem.* **18**, 199–210.
 Meriem, A., Willem, R., Biesemans, M., Mahieu, B., De Vos, D., Lelieveld, P. & Gielen, M. (1991). *Appl. Organomet. Chem.* **5**, 195–201.
 Meriem, A., Willem, R., Meunier-Piret, J., Biesemans, M., Mahieu, B. & Gielen, M. (1990). *Main Group Met. Chem.* **13**, 167–180.
 Meunier-Piret, J., Boualam, M., Willem, R. & Gielen, M. (1993). *Main Group Met. Chem.* **16**, 329–334.

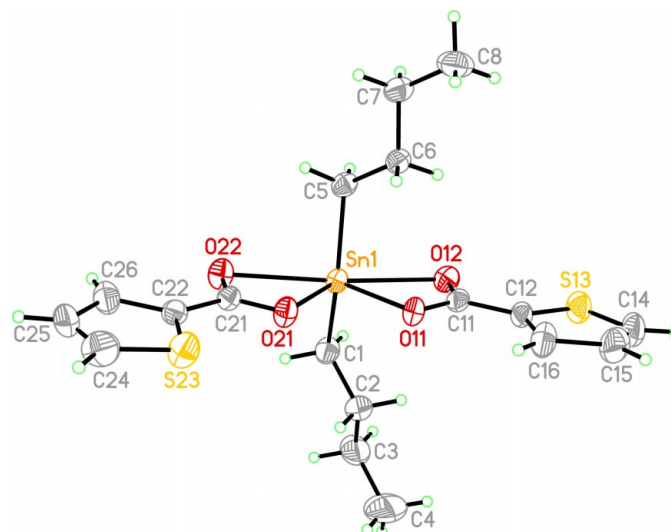


Figure 1

A perspective view of molecule 1 of the title compound with the atom-numbering scheme. Displacement ellipsoids are at the 50% probability level.

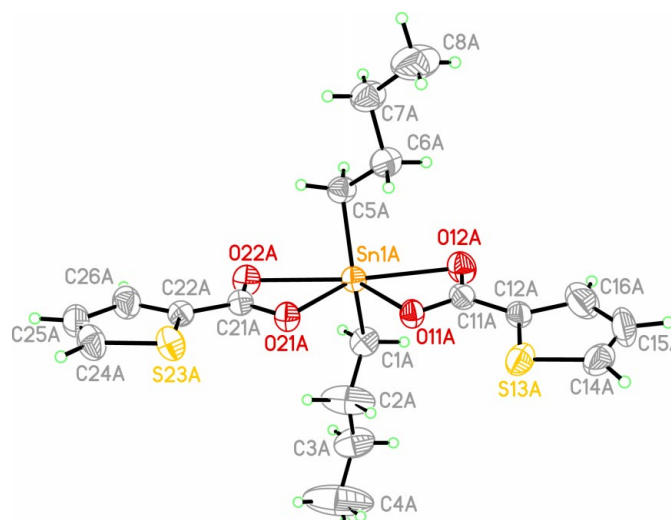


Figure 2

A perspective view of molecule 2 of the title compound with the atom-numbering scheme. Displacement ellipsoids are at the 50% probability level.

Sheldrick, G. M. (1990). *Acta Cryst.* **A46**, 467–473.
 Sheldrick, G. M. (1991). *SHELXTL-Plus*. Release 4.1. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.
 Sheldrick, G. M. (1996). *SADABS*. University of Göttingen, Germany.
 Sheldrick, G. M. (1997). *SHELXL97*. University of Göttingen, Germany.
 Siemens (1995). *SMART and SAINT*. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.